



#### **General Description**

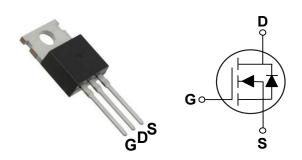
These N-Channel enhancement mode power field effect transistors are using trench MOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub>
200 V	22 mΩ	78 A

#### **Features**

- $\cdot R_{DS(ON)} \le 22 m\Omega \overline{@V_{GS}} = \overline{10V}$
- · Fast Switching
- · Green Device Available

#### TO-220 Pin Configuration



#### **Applications**

- · DC/DC Converter
- · LED Backlighting
- Motor Control

#### Absolute Maximum Ratings T<sub>C</sub>=25°C unless otherwise noted **Parameter** Symbol Rating Units $V_{DS}$ Drain-Source Voltage 200 $V_{GS}$ ٧ Gate-Source Voltage +20 78 $I_D$ Drain Current – Continuous (T<sub>C</sub>=25°C) Α $I_{DM}$ Drain Current - Pulsed (NOTE 1) 312 EAS Single Pulse Avalanche Energy (NOTE 2) 146 mJ $P_D$ 312.5 W Power Dissipation (T<sub>C</sub>=25°C) $T_{\mathsf{J}}$ -55 to 150 Operating Junction Temperature Range °C -55 to 150 $T_{STG}$ Storage Temperature Range ٥С NS022 Marking Code

Thermal Characteristics					
Symbol	Parameter	Rating	Unit		
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	55	°C/W		
$R_{ heta JC}$	Thermal Resistance Junction to Case	0.4	°C/W		





### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	200			V
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =200V , V <sub>GS</sub> =0V			1	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±20V , $V_{DS}$ =0V			±100	nA

#### On Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =20A			22	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250uA$	2		4	V

#### **Dynamic and switching Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$Q_g$	Total Gate Charge			37		
$Q_gs$	Gate-Source Charge	$V_{DS}$ =100V , $V_{GS}$ =10V , $I_{D}$ =20A		9.5		nC
$Q_{gd}$	Gate-Drain Charge			5.2		l
$T_{d(on)}$	Turn-On Delay Time			11.5		
T <sub>r</sub>	Rise Time	$V_{DS}$ =100V , $R_{G}$ =3 $\Omega$ , $I_{D}$ =20A , $V_{GS}$ =10V		18		nS
$T_{d(off)}$	Turn-Off Delay Time			18.5		110
$T_f$	Fall Time			6.8		
$C_{iss}$	Input Capacitance			2850		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =100V , V <sub>GS</sub> =0V , F=1MHz		210		pF
$C_{rss}$	Reverse Transfer Capacitance			8.5		
$R_g$	Gate Resistance	$V_{DS}$ =0V , $V_{GS}$ =0V , F=1MHz		3.3		Ω

#### **Drain-Source Diode Characteristics and Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Body Diode Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			78	Α
$V_{SD}$	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =20A			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>R</sub> =100V , I <sub>F</sub> =20A ,		110		nS
$Q_{rr}$	Reverse Recovery Charge	dI <sub>F</sub> /dt=100A/us	-	405		nC

#### NOTES:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The EAS data shows Max. rating .The test condition is  $V_{DD}$ =30V, L=0.4mH,  $V_{GS}$ =10V,  $I_{AS}$ =27A.
- 3. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **T2MNS022**



# 200V N-Channel MOSFETs

#### **Characteristics Curves**

FIG. 1-Transfer Characteristics

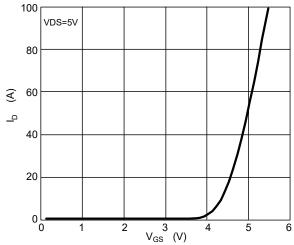


FIG. 3-R<sub>DS(on)</sub> vs I<sub>D</sub>

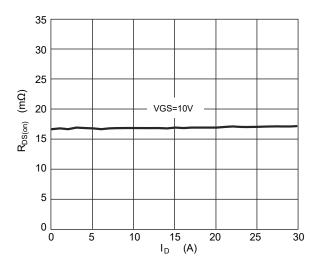


FIG. 5-Gate Charge Characteristics

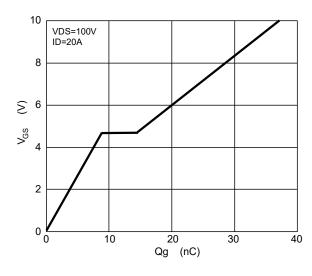


FIG. 2-I<sub>S</sub> vs V<sub>SD</sub>

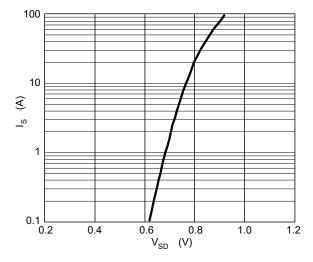


FIG. 4-Normalized  $R_{DS(on)}$  vs  $T_J$ 

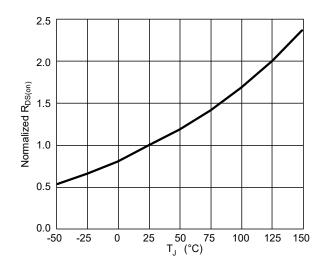
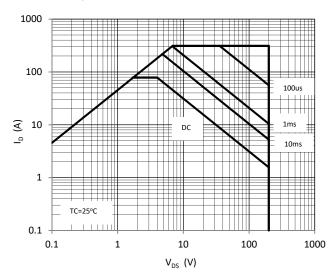


FIG. 6-Switching Time Waveform







#### **Characteristics Curves**

### FIG. 7-Normalized Maximum Transient Thermal Impedance

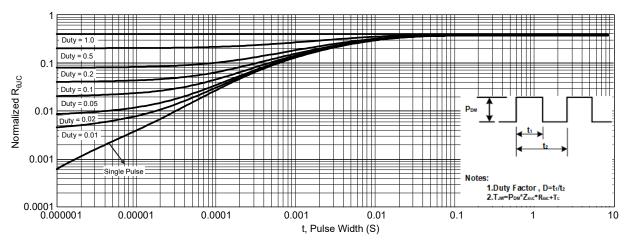


FIG. 8- Switching Time Waveform

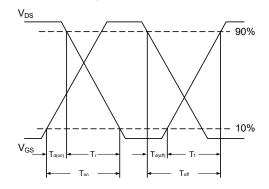
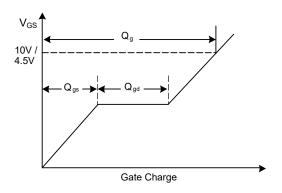
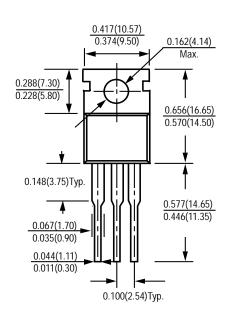
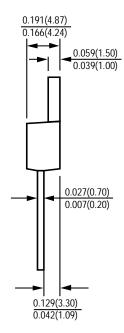


FIG. 9- Gate Charge Waveform



### **Package Outline Dimensions**





**TO-220** 

Dimensions in inches and (millimeters)





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